

[IEEE HOME](#) | [SEARCH IEEE](#) | [SHOP](#) | [WEB ACCOUNT](#) | [CONTACT IEEE](#)[Membership](#) | [Publications/Services](#) | [Standards](#) | [Conferences](#) | [Careers/Jobs](#)**IEEE Xplore®**
RELEASE 1.8Welcome
United States Patent and Trademark Office[Help](#) | [FAQ](#) | [Terms](#) | [IEEE Peer Review](#)[Quick Links](#)**Welcome to IEEE Xplore®**

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

Your search matched **0** of **1071730** documents.A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.**Refine This Search:**

You may refine your search by editing the current search expression or enter a new one in the text box.

☐ Check to search within this result set**Results Key:****JNL** = Journal or Magazine **CNF** = Conference **STD** = Standard**Results:****No documents matched your query.** **Print Format**[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved


[SPIE DL home](#) | [Scitation home](#) | [Search SPIN](#) | [help](#) | [contact](#) | [sign in](#) | [sign out](#)

SPIE Digital Library

Proceedings

Journals

**SPIE—The International
Society for Optical Engineering**
[My SPIE Subscription](#) | [My E-mail Alerts](#) | [My Article Collections](#)
[Home](#) » [Advanced Search](#) » Search Results

SEARCH DIGITAL LIBRARY

[\[Back to Search Query\]](#) | [Start New Search](#) | [Searching Hints](#)
☒ Digital SPIE Papers

☐ All SPIE Papers

[Advanced Search](#)

BROWSE PROCEEDINGS

☒ Proceedings

- ☐ By Year
- ☐ By Symposium
- ☐ By Volume No.
- ☐ By Volume Title
- ☐ By Technology

BROWSE JOURNALS

☒ Journals

- ☐ Optical Engineering
- ☐ J. Electronic Imaging
- ☐ J. Biomedical Optics
- ☐ J. Microlithography,
Microfabrication,
and Microsystems

GENERAL INFORMATION

- ☒ About the Digital Library
- ☒ Subscriptions & Pricing
- ☒ E-mail Alerts
- ☒ Terms of Use
- ☒ Companies & Institutions
- ☒ SPIEWeb

Search Results

You were searching for : ((quantizer) <and>(watermark <IN> abstract <OR> watermark <IN> title <OR> watermark <IN> keywords))

You found 5 out of 101728 (5 returned)

Documents 1 - 5 listed on this page

Options for selected articles

?

Adding to MyArticles will open a second window (Scitation login required).

[Related SPIE Products]

79%

1. ☐ **Optimality of SCS watermarking**
Robert Baeuml, Roman Tzschoppe, Andre Kaup, and
Johannes Huber
Proc. SPIE Int. Soc. Opt. Eng. **5020**, 612 (2003)
PDF (217 kB)

77%

2. ☐ **Hexagonal quantizers are not optimal for 2D data hiding**
Felix Balado and Fernando Perez-Gonzalez
Proc. SPIE Int. Soc. Opt. Eng. **5020**, 623 (2003)
PDF (145 kB)

77%

3. ☐ **Quantizer characteristics important for quantization index modulation**
Hugh Brunk
Proc. SPIE Int. Soc. Opt. Eng. **4314**, 686 (2001)
PDF (190 kB)

77%

4. ☐ **Dither modulation: a new approach to digital watermarking and information embedding**
Brian Chen and Gregory W. Wornell
Proc. SPIE Int. Soc. Opt. Eng. **3657**, 342 (1999)
PDF (580 kB)

77%

5. ☐ **Watermarking by DCT coefficient removal: a statistical approach to optimal parameter settings**
Gerhard C. Langelaar, Reginald L. Lagendijk, and Jan
Biemond
Proc. SPIE Int. Soc. Opt. Eng. **3657**, 2 (1999) PDF (2100)